

SM30N10 100V N-Channel MOSFET Features: <ul style="list-style-type: none"> <input type="checkbox"/> Low Intrinsic Capacitances. <input type="checkbox"/> Excellent Switching Characteristics. <input type="checkbox"/> Extended Safe Operating Area. <input type="checkbox"/> Unrivalled Gate Charge :$Q_g = 61.7\text{nC}$ (Typ.). <input type="checkbox"/> $\text{BV}_{\text{DSS}}=100\text{V}, I_{\text{D}}=30\text{A}$ <input type="checkbox"/> $R_{\text{DS(on)}} : 0.032\Omega$ (Max) @ $V_G=10\text{V}$ <input type="checkbox"/> 100% Avalanche Tested 	TO-252 1. Gate (G) 2. Drain (D) 3. Source (S)
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Absolute Maximum Ratings* (T_c=25°C Unless otherwise noted)

Symbol	PARAMETER	Value	Unit
V_{DSS}	Drain-Source Voltage	100	V
I_{D}	Drain Current	$T_c=25^\circ\text{C}$	30
		$T_c=100^\circ\text{C}$	21
$V_{\text{GS(TH)}}$	Gate Threshold Voltage	± 20	V
E_{AS}	Single Pulse Avalanche Energy (note1)	256	mJ
I_{AR}	Avalanche Current (note2)	30	A
P_{D}	Power Dissipation ($T_c=25^\circ\text{C}$)	85	W
T_j	Junction Temperature(MAX)	175	°C
T_{stg}	Storage Temperature	-55~+175	°C
TL	Maximum lead temperature for soldering purpose, 1/8" from case for 5 seconds	300	°C

Thermal Characteristics

Symbol	PARAMETER	Typ.	MAX.	Unit
$R_{\theta\text{JC}}$	Thermal Resistance,Junction to Case	-	1.8	°C/W
$R_{\theta\text{JA}}$	Thermal Resistance,Junction to Ambient	-	65	°C/W
$R_{\theta\text{CS}}$	Thermal Resistance,Case to Sink	-	110	°C/W

Electrical Characteristics ($T_c=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Condition	Min	Typ	Max	Unit
Off Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$	100	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{\text{DS}}=100\text{V}, V_{\text{GS}}=0\text{V}$	-	-	1	μA
I_{GSS}	Gate-Body Leakage Current	$V_{\text{GS}}=\pm 20\text{V}, V_{\text{DS}}=0\text{V}$	-	-	± 100	nA
On Characteristics <small>(Note 3)</small>						
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=250\mu\text{A}$	1.3	1.8	2.5	V
$R_{\text{DS(ON)}}$	Drain-Source On-State Resistance	$V_{\text{GS}}=10\text{V}, I_{\text{D}}=10\text{A}$	-	25	32	$\text{m}\Omega$
G_{FS}	Forward Transconductance	$V_{\text{DS}}=5\text{V}, I_{\text{D}}=10\text{A}$	-	15	-	S
Dynamic Characteristics <small>(Note 4)</small>						
C_{iss}	Input Capacitance	$V_{\text{DS}}=50\text{V}, V_{\text{GS}}=0\text{V}, F=1.0\text{MHz}$	-	2356	-	PF
C_{oss}	Output Capacitance		-	94	-	PF
C_{rss}	Reverse Transfer Capacitance		-	83.3	-	PF
Switching Characteristics <small>(Note 4)</small>						
$t_{\text{d(on)}}$	Turn-on Delay Time	$V_{\text{DD}}=50\text{V}, R_{\text{L}}=5\Omega$ $V_{\text{GS}}=10\text{V}, R_{\text{GEN}}=3\Omega$	-	7	-	nS
t_r	Turn-on Rise Time		-	7	-	nS
$t_{\text{d(off)}}$	Turn-Off Delay Time		-	29	-	nS
t_f	Turn-Off Fall Time		-	7	-	nS
Q_g	Total Gate Charge	$V_{\text{DS}}=50\text{V}, I_{\text{D}}=10\text{A}, V_{\text{GS}}=10\text{V}$	-	61.7	-	nC
Q_{gs}	Gate-Source Charge		-	8.3	-	nC
Q_{gd}	Gate-Drain Charge		-	16.7	-	nC
Drain-Source Diode Characteristics						
V_{SD}	Diode Forward Voltage <small>(Note 3)</small>	$V_{\text{GS}}=0\text{V}, I_{\text{S}}=10\text{A}$	-	-	1.2	V
I_{S}	Diode Forward Current <small>(Note 2)</small>	-	-	-	30	A
t_{rr}	Reverse Recovery Time	$T_J = 25^\circ\text{C}, IF = 10\text{A}$ $di/dt = 100\text{A}/\mu\text{s}$ <small>(Note 3)</small>	-	32	-	nS
Q_{rr}	Reverse Recovery Charge		-	53	-	nC
t_{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2. Surface Mounted on FR4 Board, $t \leq 10$ sec.
3. Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$.
4. Guaranteed by design, not subject to production
5. EAS Condition : $T_j=25^\circ\text{C}, V_{\text{DD}}=50\text{V}, V_{\text{G}}=10\text{V}, L=0.5\text{mH}, R_g=25\Omega, I_{\text{AS}}=32\text{A}$

Typical Characteristics

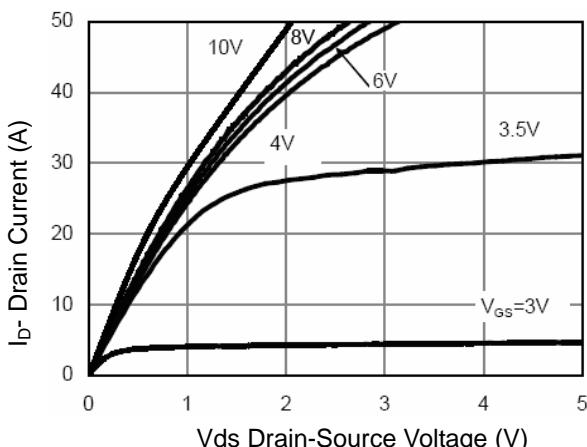


Figure 1 Output Characteristics

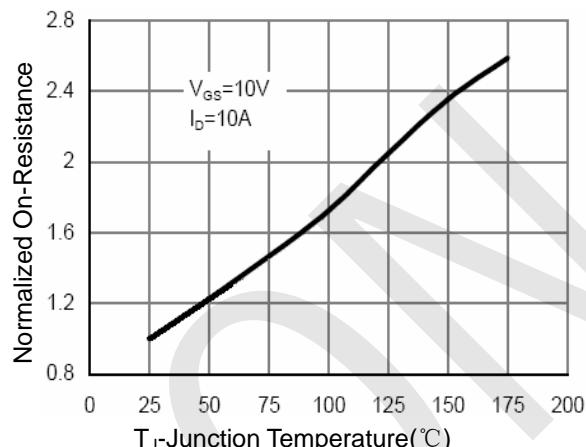


Figure 4 $R_{DS(on)}$ -JunctionTemperature

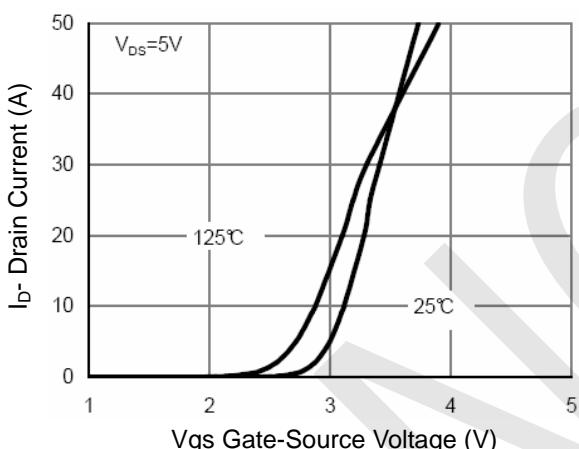


Figure 2 Transfer Characteristics

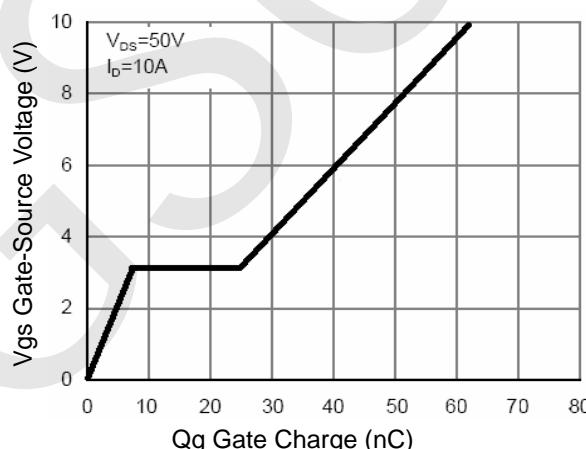


Figure 5 Gate Charge

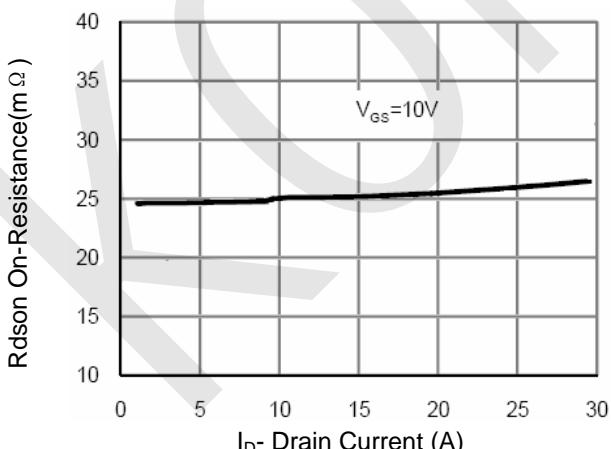


Figure 3 $R_{DS(on)}$ - Drain Current

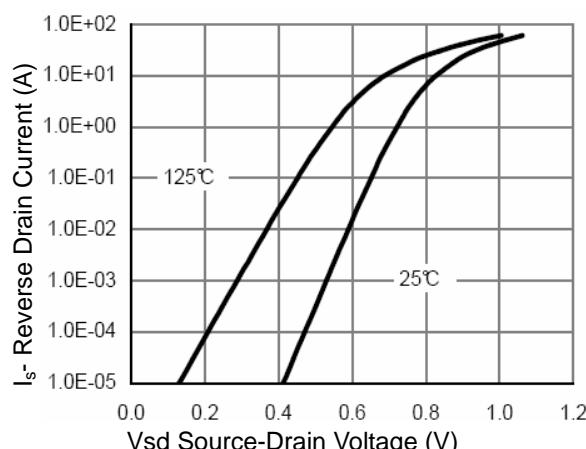


Figure 6 Source- Drain Diode Forward

Typical Characteristics (Continued)

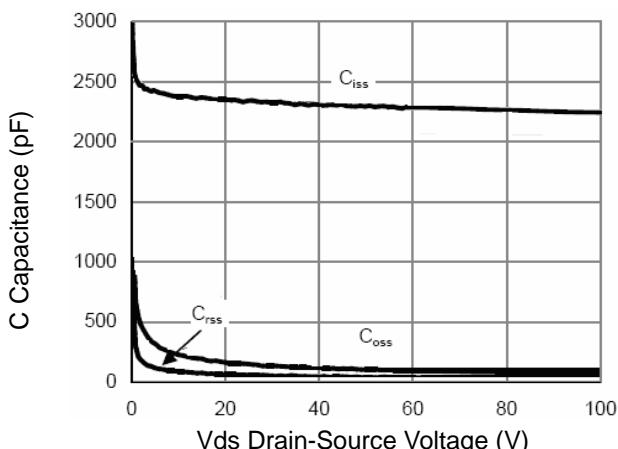


Figure 7 Capacitance vs Vds

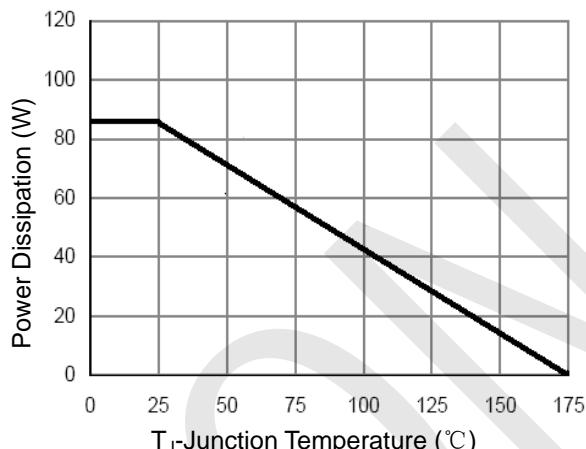


Figure 9 Power De-rating

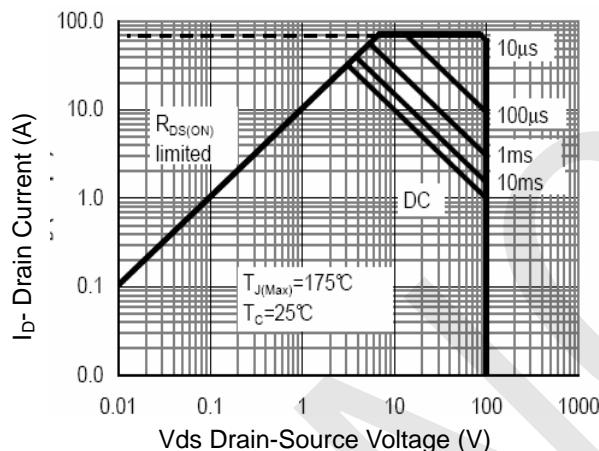


Figure 8 Safe Operation Area

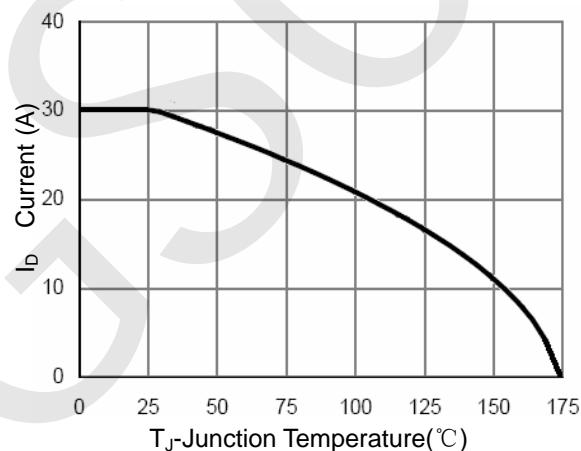


Figure 10 ID Current- Junction Temperature

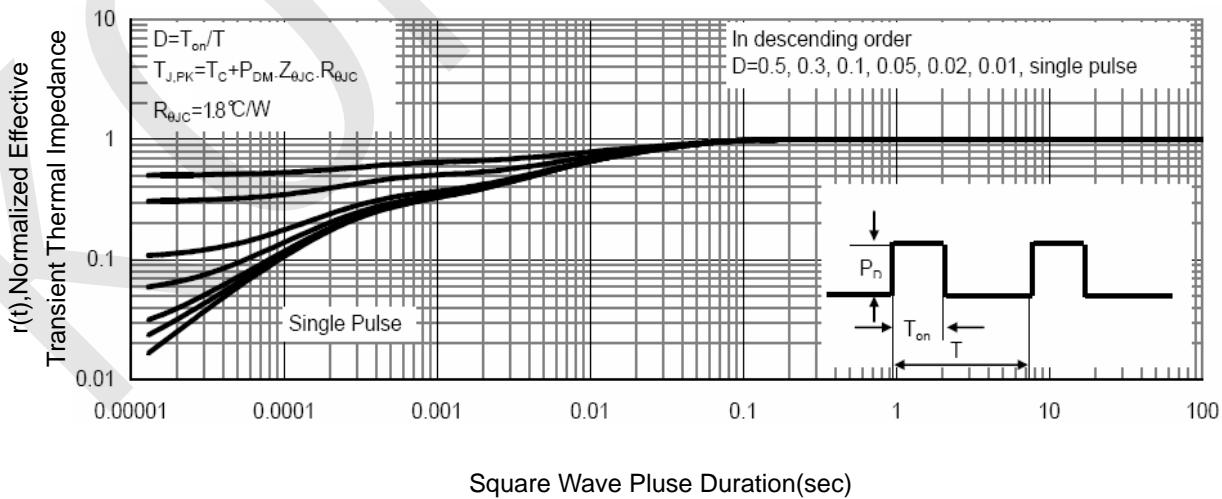
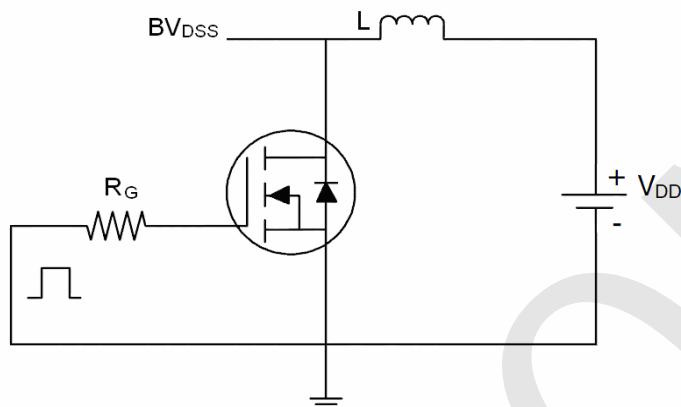


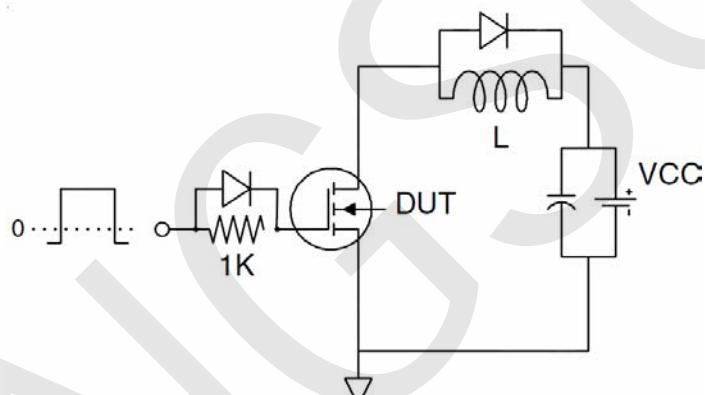
Figure 11 Normalized Maximum Transient Thermal Impedance

Test Circuit

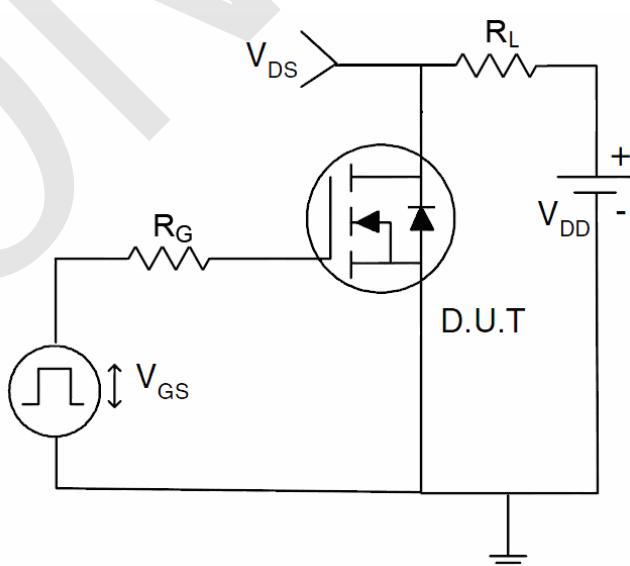
1) AS Test Circuit



2) Gate Charge Test Circuit



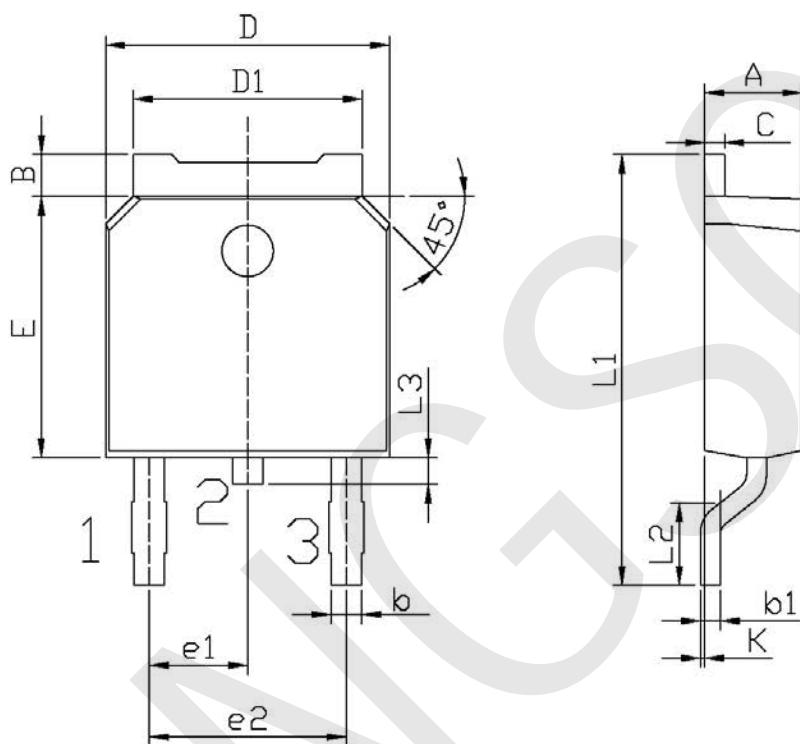
3) Switch Time Test Circuit



Package Dimension

TO-252

Unit:mm



Symbol	Dimensions In Millimeters		Symbol	Dimensions In Millimeters	
	Min	Max		Min	Max
A	2.20	2.40	E	5.95	6.25
B	0.95	1.25	e1	2.24	2.34
b	0.70	0.90	e2	4.43	4.73
b1	0.45	0.55	L1	9.85	10.35
C	0.45	0.55	L2	1.25	1.75
D	6.45	6.75	L3	0.60	0.90
D1	5.20	5.40	K	0.00	0.10